

| Type | Hits | Search Text   | DBs   | Time Stamp       | Comments | Error Definition |
|------|------|---|---|------------------|----------|------------------|
| 1    | BRS  | 11322 oxynitride  | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 08:40 |          |                  |
| 2    | BRS  | 329273 nitrogen adj1 rich adj\$n plasma   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 08:41 |          |                  |
| 3    | BRS  | 5225 oxynitride and (nitrogen adj1 rich adj\$n plasma)  | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 08:42 |          |                  |
| 4    | BRS  | 5208 ((oxynitride and (nitrogen adj1 rich adj\$n plasma)) and (nitrogen or plasma or enrich\$5 or rich\$3))   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 08:42 |          |                  |
| 5    | BRS  | 1894 ((oxynitride and (nitrogen adj1 rich adj\$n plasma)) and (nitrogen or plasma or enrich\$5 or rich\$3)) and ((("N.sub.20" or ("N.sub.2") or ("NH.sub.3"))))   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 08:43 |          |                  |
| 6    | BRS  | 1887 (((oxynitride and (nitrogen adj1 rich adj\$n plasma)) and (nitrogen or plasma or enrich\$5 or rich\$3)) and ((("N.sub.20" or ("N.sub.2") or ("NH.sub.3"))))) and (thickness or thick\$5 or angstroms or ("N.sub.2")))  | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 08:45 |          |                  |
| 7    | BRS  | 158 (((oxynitride and (nitrogen adj1 rich adj\$n plasma)) and (nitrogen or plasma or enrich\$5 or rich\$3)) and ((("N.sub.20" or ("N.sub.2") or ("NH.sub.3"))))) and (thickness or thick\$5 or angstroms or ("N.sub.2")))) and ONO  | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 08:46 |          |                  |
| 8    | BRS  | 158 (((((oxynitride and (nitrogen adj1 rich adj\$n plasma)) and (nitrogen or plasma or enrich\$5 or rich\$3)) and ((("N.sub.20" or ("N.sub.2") or ("NH.sub.3"))))) and (thickness or thick\$5 or angstroms or ("N.sub.2")))) and ONO) and (plasma or nitrogen or nitride)   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 08:47 |          |                  |
| 9    | BRS  | 535681 (((((oxynitride and (nitrogen adj1 rich adj\$n plasma)) and (nitrogen or plasma or enrich\$5 or rich\$3)) and ((("N.sub.20" or ("N.sub.2") or ("NH.sub.3"))))) and (thickness or thick\$5 or angstroms or ("N.sub.2")))) and ONO) and (plasma or nitrogen or nitride)) or (rich\$3 or enrich\$3)   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 08:48 |          |                  |
| 10   | BRS  | 40 ((((((oxynitride and (nitrogen adj1 rich adj\$n plasma)) and (nitrogen or plasma or enrich\$5 or rich\$3)) and ((("N.sub.20" or ("N.sub.2") or ("NH.sub.3"))))) and (thickness or thick\$5 or angstroms or ("N.sub.2")))) and ONO) and (plasma or nitrogen or nitride)) and (rich\$3 or enrich\$3)   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 09:12 |          |                  |
| 11   | BRS  | 5 "6100559"   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/21 09:12 |          |                  |
| 12   | BRS  | 1155024 semiconductor   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 10:29 |          |                  |
| 13   | BRS  | 62695 semiconductor and (tensil\$4 adj\$n stress)   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 10:30 |          |                  |
| 14   | BRS  | 10546 (semiconductor and (tensil\$4 adj\$n stress)) and impurit\$4  | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 10:31 |          |                  |
| 15   | BRS  | 101 ((semiconductor and (tensil\$4 adj\$n stress)) and impurit\$4) and (dyn\$3)   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 10:32 |          |                  |
| 16   | BRS  | 942 ((semiconductor and (tensil\$4 adj\$n stress)) and impurit\$4) and (LPCVD)  | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 10:34 |          |                  |
| 17   | BRS  | 934 ((semiconductor and (tensil\$4 adj\$n stress)) and impurit\$4) and (LPCVD) and (gas or chlorine or (silicon adj1 nitride) or ("Si.sub.3 N.sub.4") or N or Si or nitride) or ("Si.sub.3 N.sub.4") or N or Si or nitride)   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 10:36 |          |                  |
| 18   | BRS  | 404 (((semiconductor and (tensil\$4 adj\$n stress)) and impurit\$4) and (LPCVD)) and (gas or chlorine or (silicon adj1 nitride) or ("Si.sub.3 N.sub.4") or N or Si or nitride) and (mixt\$5 or ("SiCl.sub.4") or ("SiH.sub.2 Cl.sub.2") or ("SiCl.sub.3") or ("Si.sub.2 Cl.sub.6")))  | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 10:40 |          |                  |
| 19   | BRS  | 402 (((((semiconductor and (tensil\$4 adj\$n stress)) and impurit\$4) and (LPCVD)) and (gas or chlorine or (silicon adj1 nitride) or ("Si.sub.3 N.sub.4") or N or Si or nitride)) and (mixt\$5 or ("SiCl.sub.4") or ("SiH.sub.2 Cl.sub.2") or ("SiCl.sub.3") or ("Si.sub.2 Cl.sub.6")))) and (Torr or temperature or ratio or element))   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 10:42 |          |                  |
| 20   | BRS  | 2 50 and (prssure or get\$6 or contact\$6)  | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 10:46 |          |                  |
| 21   | BRS  | 398 (((((semiconductor and (tensil\$4 adj\$n stress)) and impurit\$4) and (LPCVD)) and (gas or chlorine or (silicon adj1 nitride) or ("Si.sub.3 N.sub.4") or N or Si or nitride)) and (mixt\$5 or ("SiCl.sub.4") or ("SiH.sub.2 Cl.sub.2") or ("SiCl.sub.3") or ("Si.sub.2 Cl.sub.6")))) and (Torr or temperature or ratio or element)) and (pressure or get\$6 or contact\$6))   | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 11:37 |          |                  |
| 22   | BRS  | 392 ((((((((semiconductor and (tensil\$4 adj\$n stress)) and impurit\$4) and (LPCVD)) and (gas or chlorine or (silicon adj1 nitride) or ("Si.sub.3 N.sub.4") or N or Si or nitride)) and (mixt\$5 or ("SiCl.sub.4") or ("SiH.sub.2 Cl.sub.2") or ("SiCl.sub.3") or ("Si.sub.2 Cl.sub.6")))) and (Torr or temperature or ratio or element)) and (pressure or get\$6 or contact\$6)) and (tens\$6 or stress\$4)) and (dyne) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 11:58 |          |                  |
| 23   | BRS  | 0 (((((((semiconductor and (tensil\$4 adj\$n stress)) and impurit\$4) and (LPCVD)) and (gas or chlorine or (silicon adj1 nitride) or ("Si.sub.3 N.sub.4") or N or Si or nitride)) and (mixt\$5 or ("SiCl.sub.4") or ("SiH.sub.2 Cl.sub.2") or ("SiCl.sub.3") or ("Si.sub.2 Cl.sub.6")))) and (Torr or temperature or ratio or element)) and (pressure or get\$6 or contact\$6)) and (tens\$6 or stress\$4)) and (dyne)    | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 11:58 |          |                  |
| 24   | BRS  | 55 (((((((semiconductor and (tensil\$4 adj\$n stress)) and impurit\$4) and (LPCVD)) and (gas or chlorine or (silicon adj1 nitride) or ("Si.sub.3 N.sub.4") or N or Si or nitride)) and (mixt\$5 or ("SiCl.sub.4") or ("SiH.sub.2 Cl.sub.2") or ("SiCl.sub.3") or ("Si.sub.2 Cl.sub.6")))) and (Torr or temperature or ratio or element)) and (pressure or get\$6 or contact\$6)) and (tens\$6 or stress\$4)) and tensile  | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 12:35 |          |                  |

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|----|------|------|---|--|------------------|----------|------------------|
| 25 | BRS  | 6    | (((((semiconductor and (tensi\$4 adj\$N stress)) and impuri\$4) and (LPCVD)) and (gas or chlorine or (silicon adj1 nitride) or ("Si.sub.3 N.sub.4") or N or Si or nitride)) and (mixt\$5 or ("SiCl.sub.4") or ("SiH.sub.2 Cl.sub.2") or ("SiCl.sub.3") or ("Si.sub.2 Cl.sub.6")))) and (Torr or (temperature or ratio or element)) and (pressure or get\$6 or contact\$6)) and (tens\$6 or stress\$4)) and (tensile) and (dyn\$4) | USPAT; US-PPGPUB; EPO; JPO; DERWENT; IBM_TDB | 2002/10/24 12:36 |          |                  |